

## Search Notes



**Application/Control No.**

10/645 244

**Examiner**

Shih-Chao Chen

**Applicant(s)/Patent under  
Reexamination**

MEIER ET AL

## ART UNIT

2821

**SEARCHED**

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
343	700MS	3/7/2005	CHEN
343	757, 853	3/7/2005	CHEN

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**